JUL 2 3 2007 ńnu K. Agarwal, et al.

Title:

Capacitor Constructions With Enhanced Surface Area

Assignee:

Micron Technology, Inc.

Serial No.: 10/050,334

Filed:

January 15, 2002 [RCE filed herewith]

Our Ref.:

MI22-1913

INFORMATION DISCLOSURE STATEMENT

PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98

The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to Federal Register, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art are attached. No admission is made regarding whether the listed references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated:

By:

James Reg. No.44,854 Wells St. John P.S. Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE (Use several sheets if necessary),

ATTY. DOCKET NO. MI22-1913

SERIAL NO. 10/050,334

APPLICANT: Vishnu K. Agarwal

FILING DATE January 15, 2002

GROUP 2813

U.S. PATENT DOCUMENTS

*Examiner's								
Initials		Document Number	Date	Name	Class	Subclass	Filing If Appre	Date opriate
	AA	5,187,637	02/93	Embree				
	AB	5,444,013	08/95	Akram, et al.				
	AC	5,899,725	05/99	Harshfield				
	AD	5,905,280	05/99	Liu, et al				
	AE	5,972,769	10/99	Tsu, et al.				
	AF	6,262,469	07/01	Le et al.		·		
	AG	6,291,850	09/01	Choi et al.				
!	АН	6,363,691	04/02	Flaherty				
•	AI		į					
· FOREIGN F	PATENT	DOCUMENTS					<u> </u>	
		Document	Date	Country	Class	Subclass	Translation	
	l	Number	1 !	,				1
	AJ	Number					Yes	No
	AJ	Number						No
	-	Number						No
OTHER RE	AK AL	Number CES (including Author, T	itle, Date, Pert					No
OTHER RE	AK AL		itle, Date, Pert					No
OTHER RE	AK AL FEREN		itle, Date, Pert					No
OTHER RE	AK AL FEREN		itle, Date, Pert					No
OTHER RE	AK AL FEREN AM		itle, Date, Pert					No
OTHER RE	AK AL FEREN AM AN AO							No

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.